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L31	l18 and l22	28	L31
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L29	l18 and l20	124	L29
L28	l18 and l26	218	L28
L27	L26 and l19	34	L27
L26	(712/2-300)[CCLS]	12719	L26
L25	l19 and l22	4	L25
L24	l19 and l21	11	L24
L23	l19 and l20	21	L23
L22	(711/132)[CCLS]	145	L22
L21	(711/120-173)[CCLS]	19825	L21

L20	(712/200-219,225-227, 241-248)![CCLS]	5783	L20

DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR

L19	L18 and (thread$3 or multi near1 thrread$3)	90	L19
L18	push$4 near25 pop$4 near25 stack near25 point$3	549	L18
L17	push$4 near25 pop$4 near25 stack near25 (sram or static) near25 point$3	0	L17

DB=USPT; PLUR=YES; OP=OR

L16	l3 and memor$4	1	L16
L15	L14 and (push or pop)	29	L15
L14	stack near5 sram	109	L14
L13	L12 and sram	0	L13
L12	5946487.pn.	1	L12
L11	L10 and sram	0	L11
L10	5968169.pn.	1	L10
L9	L8 and sram	0	L9
L8	3889243.pn.	1	L8
L7	L4 and ram$1	0	L7
L6	L4 and sram$1	0	L6
L5	L4 and sram	0	L5
L4	L3 and offset	1	L4
L3	5542070.pn.	1	L3
L2	associat$3 near8 pop near8 push	54	L2
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IEEE JNL	IEEE Journal or Magazine
IEE JNL	IEE Journal or Magazine
IEEE CNF	IEEE Conference Proceeding
IEE CNF	IEE Conference Proceeding
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```
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▢   1. **Abstracting stack to detect obfuscated calls in binaries**
Lakhotia, A.; Kumar, E.U.;
Source Code Analysis and Manipulation, 2004. Fourth IEEE International Workshop on
2004 Page(s):17 - 26
Digital Object Identifier 10.1109/SCAM.2004.2

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▢   2. **StackOFFence: a technique for defending against buffer overflow attacks**
Madan, B.B.; Phoha, S.; Trivedi, K.S.;
Information Technology: Coding and Computing, 2005. ITCC 2005. International Conference on
Volume 1, 4-6 April 2005 Page(s):656 - 661 Vol. 1
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Plasma Science, 2004. ICOPS 2004. IEEE Conference Record - Abstracts. The 31st IEEE Internat
28 June-1 July 2004 Page(s):444
Digital Object Identifier 10.1109/PLASMA.2004.1340259

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Ramanathan, L.N.; Mitchell, D.;
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21-24 May 2000 Page(s):837 - 843
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▢   5. **3-D PIC simulations of electron flow in the vacuum power flow section of the Z accelerator**
Pointon, T.D.;
Pulsed Power Plasma Science, 2001. IEEE Conference Record - Abstracts
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Digital Object Identifier 10.1109/PPPS.2001.961335

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6. **An evaluation of regular path expressions with qualifiers against XML streams**
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Data Engineering, 2003. Proceedings. 19th International Conference on
5-8 March 2003 Page(s):702 - 704

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Ramanathan, L.N.; Mitchell, D.;
Components and Packaging Technologies, IEEE Transactions on [see also Components, Packagir Technology, Part A: Packaging Technologies, IEEE Transactions on]
Volume 24, Issue 3, Sept. 2001 Page(s):425 - 430
Digital Object Identifier 10.1109/6144.946489

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